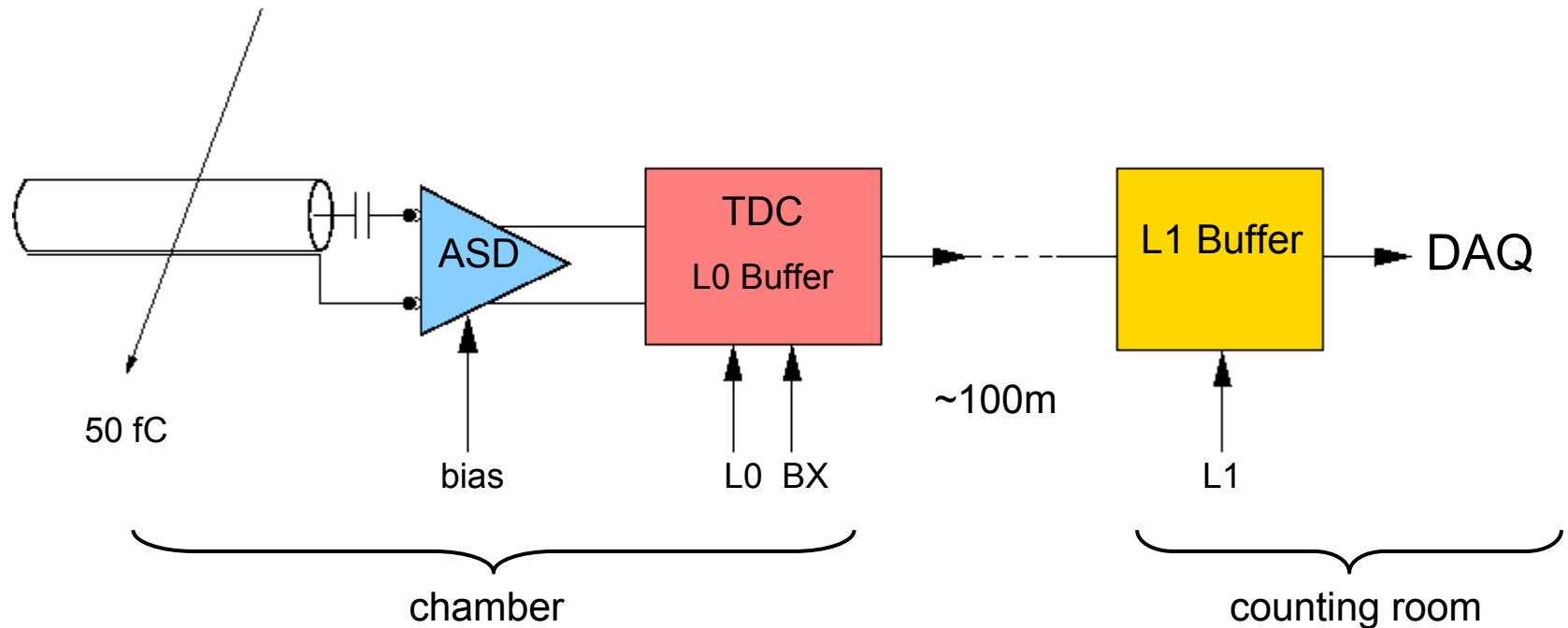
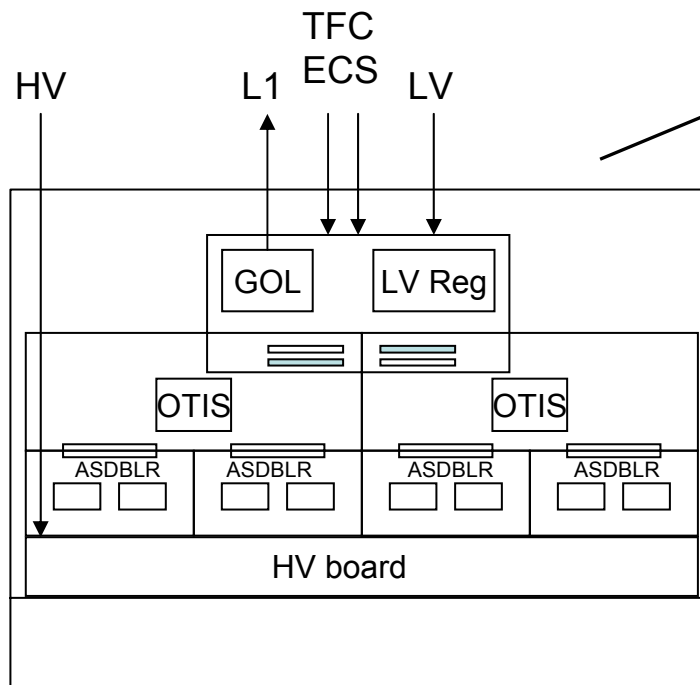


Outer Tracker Electronics





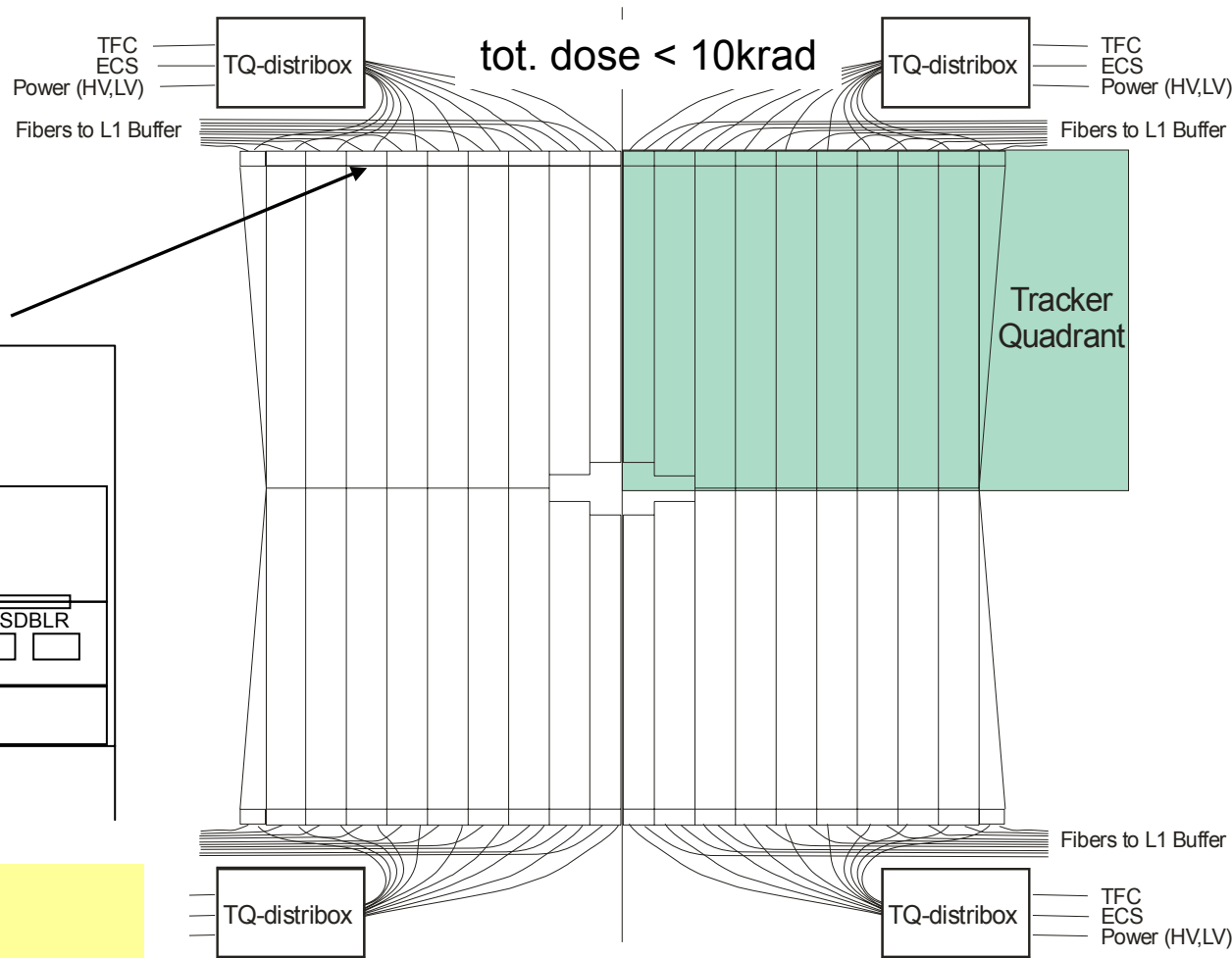
Module End:

128 channels

16 ASDBLR chips

4 OTIS TDC chips

1 optical link: 1.28 Gbit/s

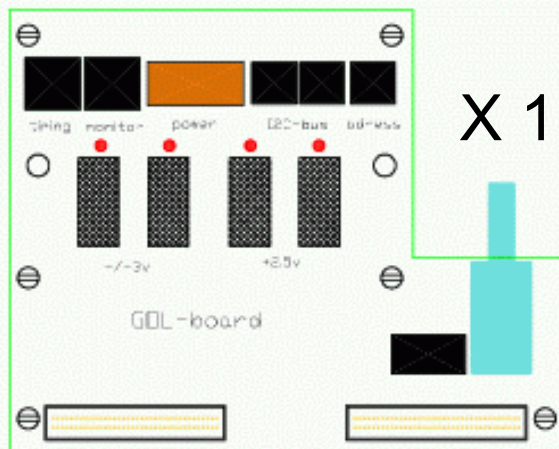


Outer Tracker: ST1...3

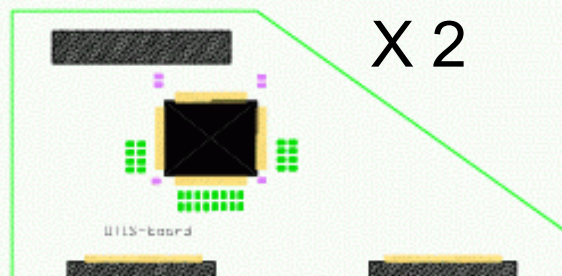
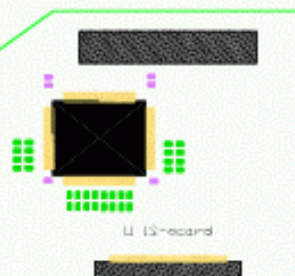
56000 channels

432 optical links

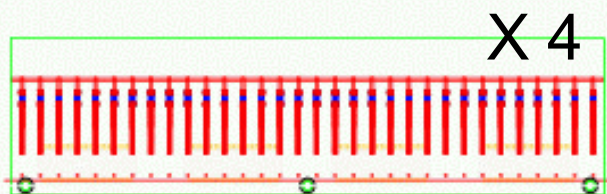
GOL/Aux Board



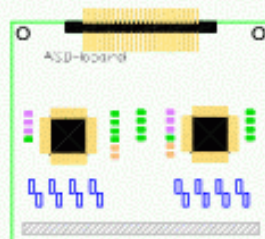
TDC boards



HV boards



ASD boards

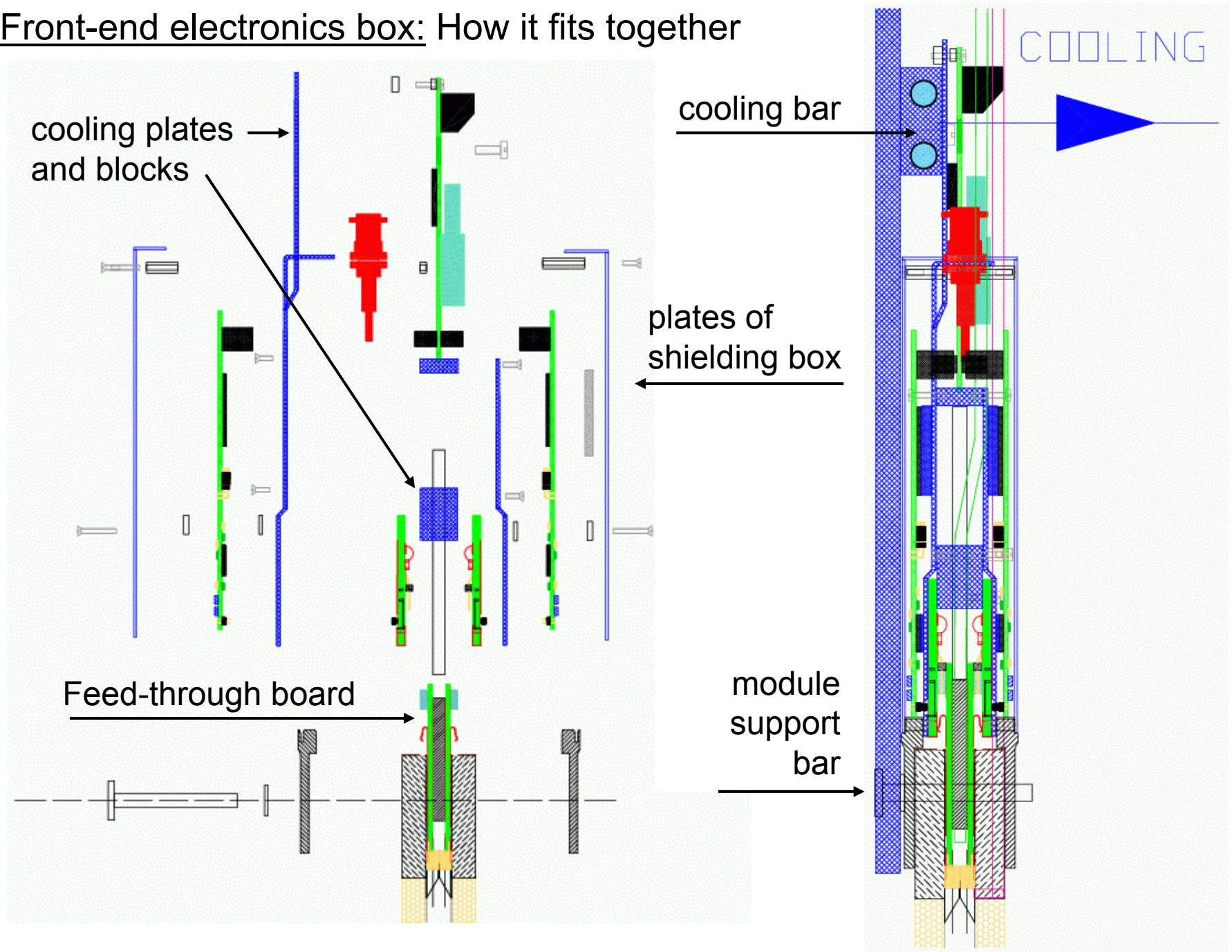


X 8

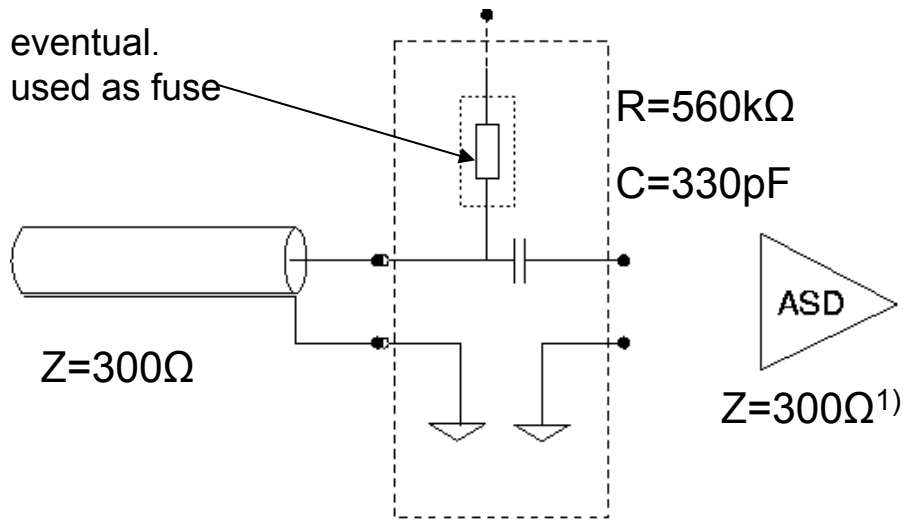
Front-end cards:

- have to fit inside a closed metal shielding box: 22 x 30 x 4 cm
- excellent ground connection to straw-tubes and module reference ground
- power dissipation of cards is about 22 W / box → water cooling
- easy access should be maintained

Front-end electronics box: How it fits together



HV Boards

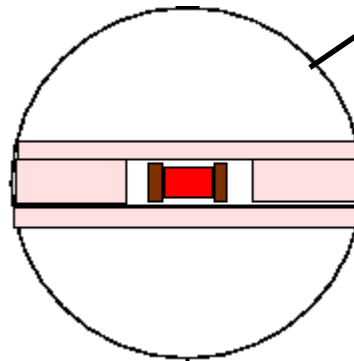
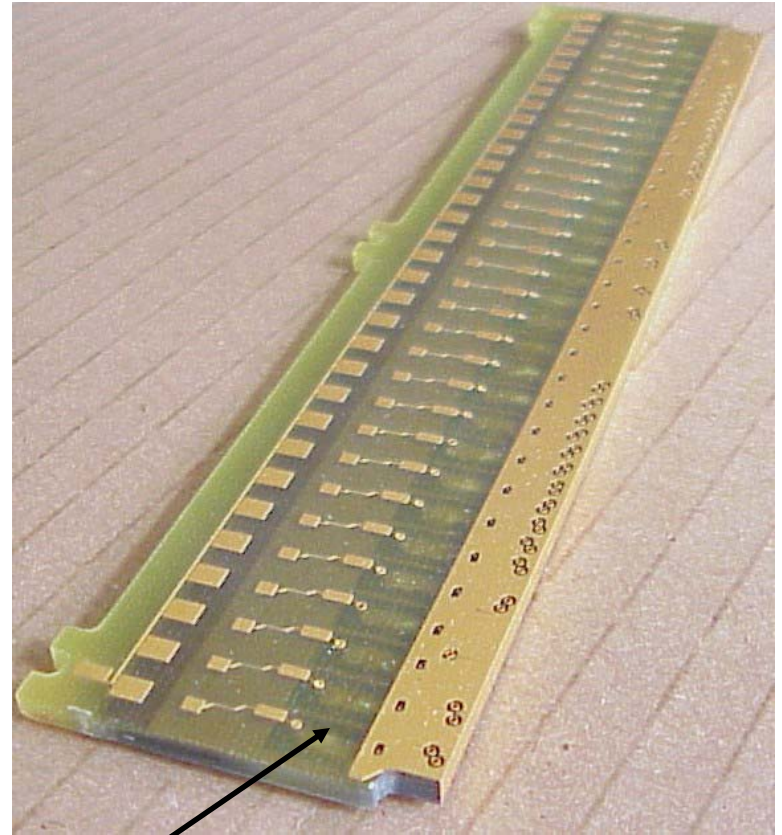


Capacitors:

JOHANSON 302R29W331KV4E

Max. Volt.: 4kV

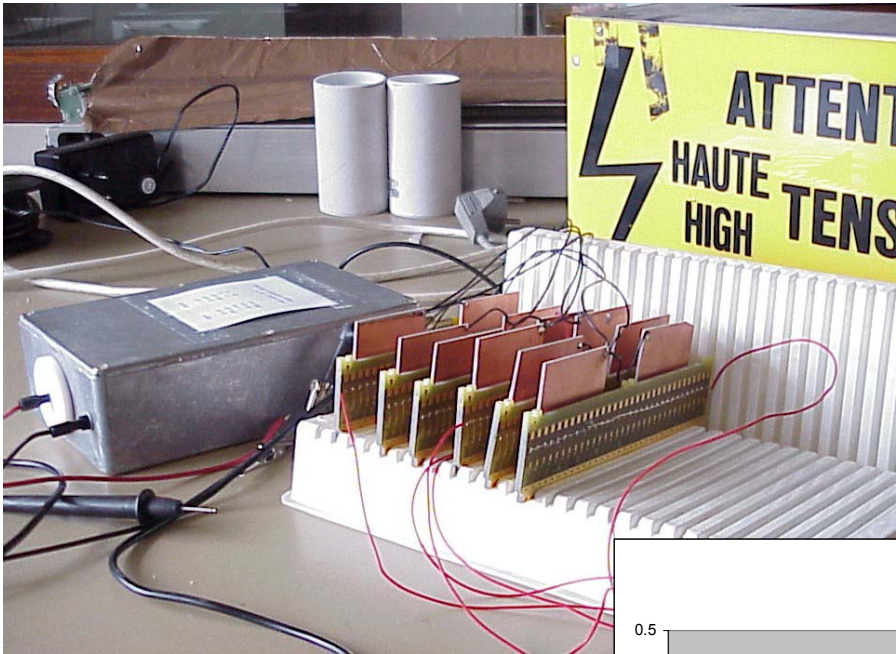
Size: $4.6 \times 2 \times 1.5 \text{ mm}^3$



32 channels per board

Capacitors embedded in PCB:

¹⁾ $Z=150\Omega$ at high frequencies + 150Ω in series



Long term tests:

19 boards = 608 channels

1. HV = +2.5 KV, t = 14 days

→ I (32 cha) < 50 nA

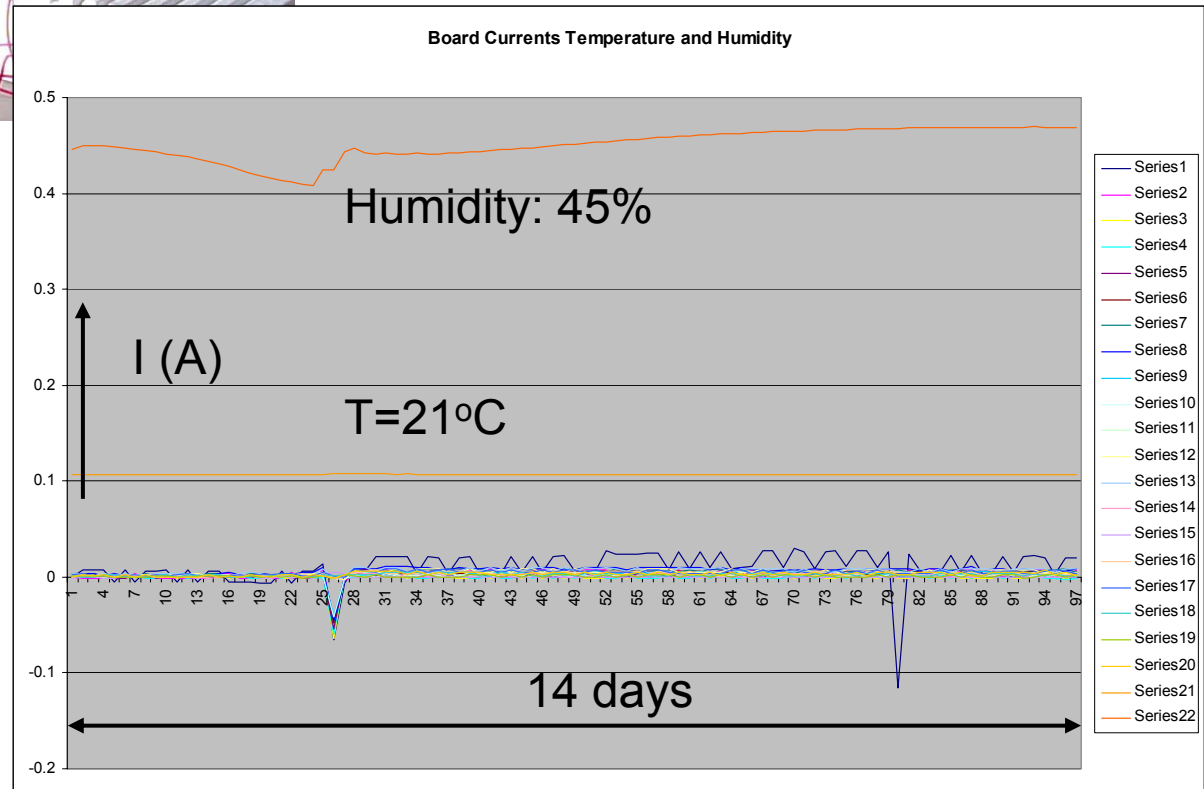
→ 1 failing cap

2. Temperature cycling:

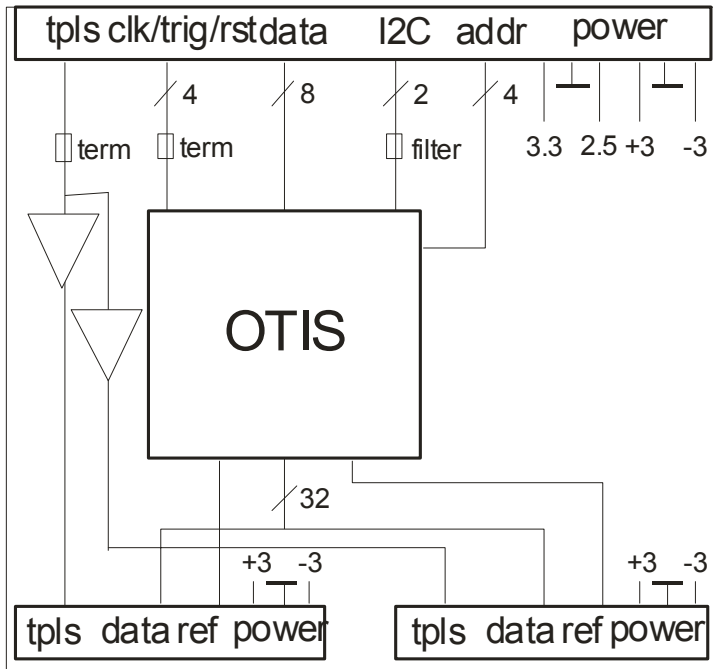
every hour 25-65°C

HV = +2.5 KV, t = 14 days

→ 1 failing cap



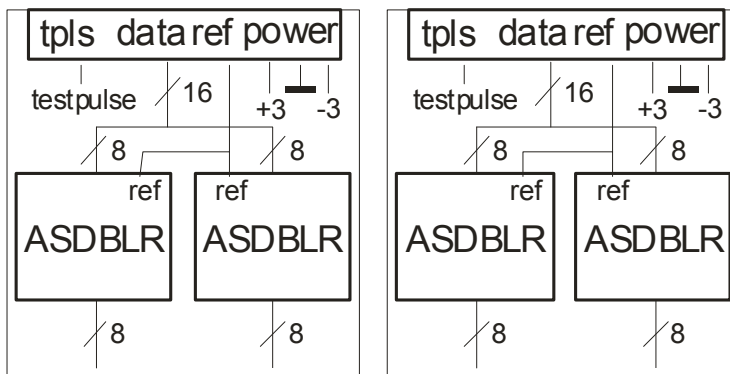
➡ More studies needed



min.
42 pins
connector

TDC board:

- radiation hard OTIS TDC chip
- provides bias voltage for ASD
- power rooting for ASDBLR card
- test pulses for ASDBLR



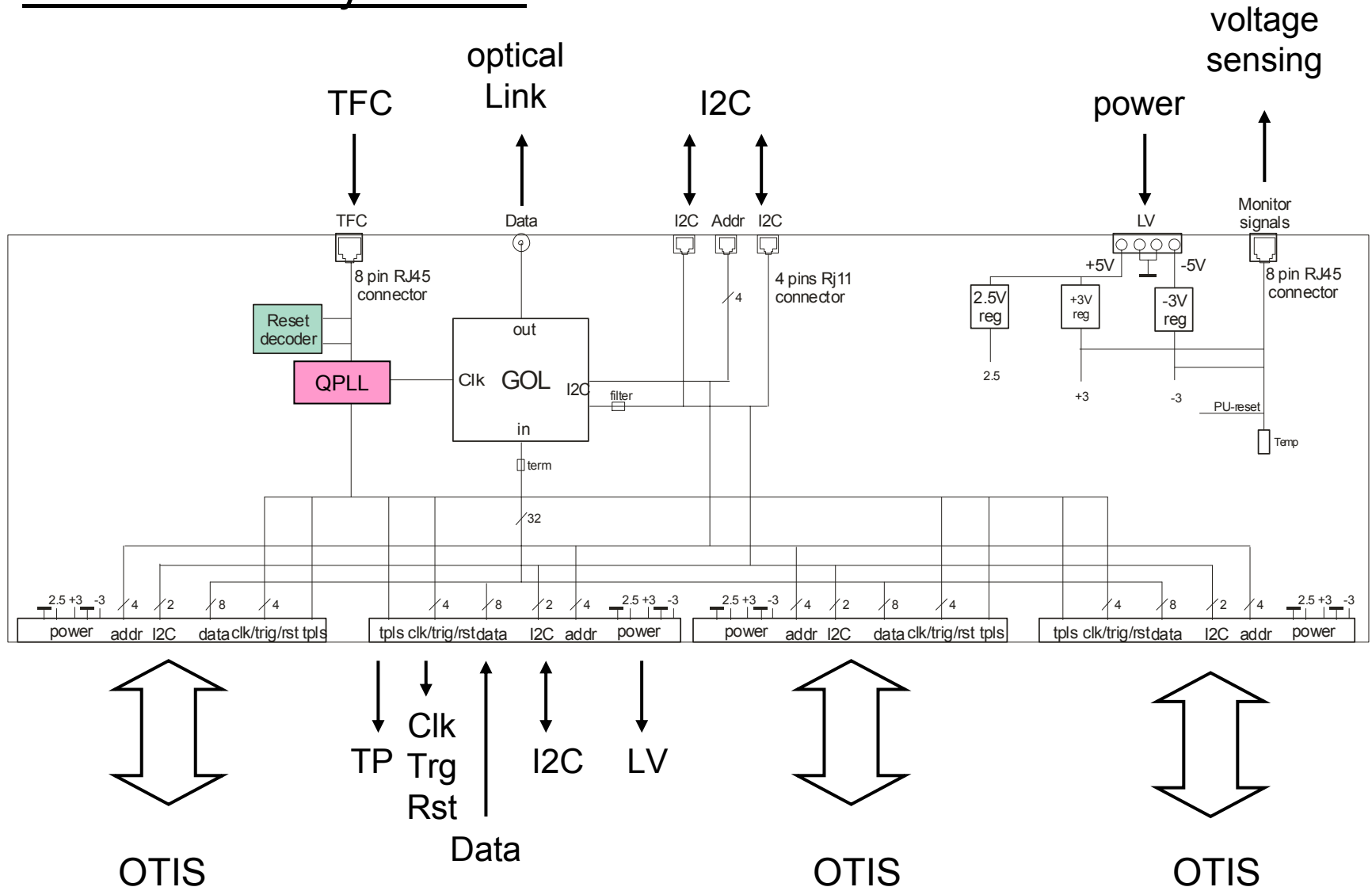
min.
38 pins
connector

ASDBLR chip:

ATLAS DMILL version 02

⇒ joining ATLAS chip order

GOL / Auxiliary Board: Interface to outside

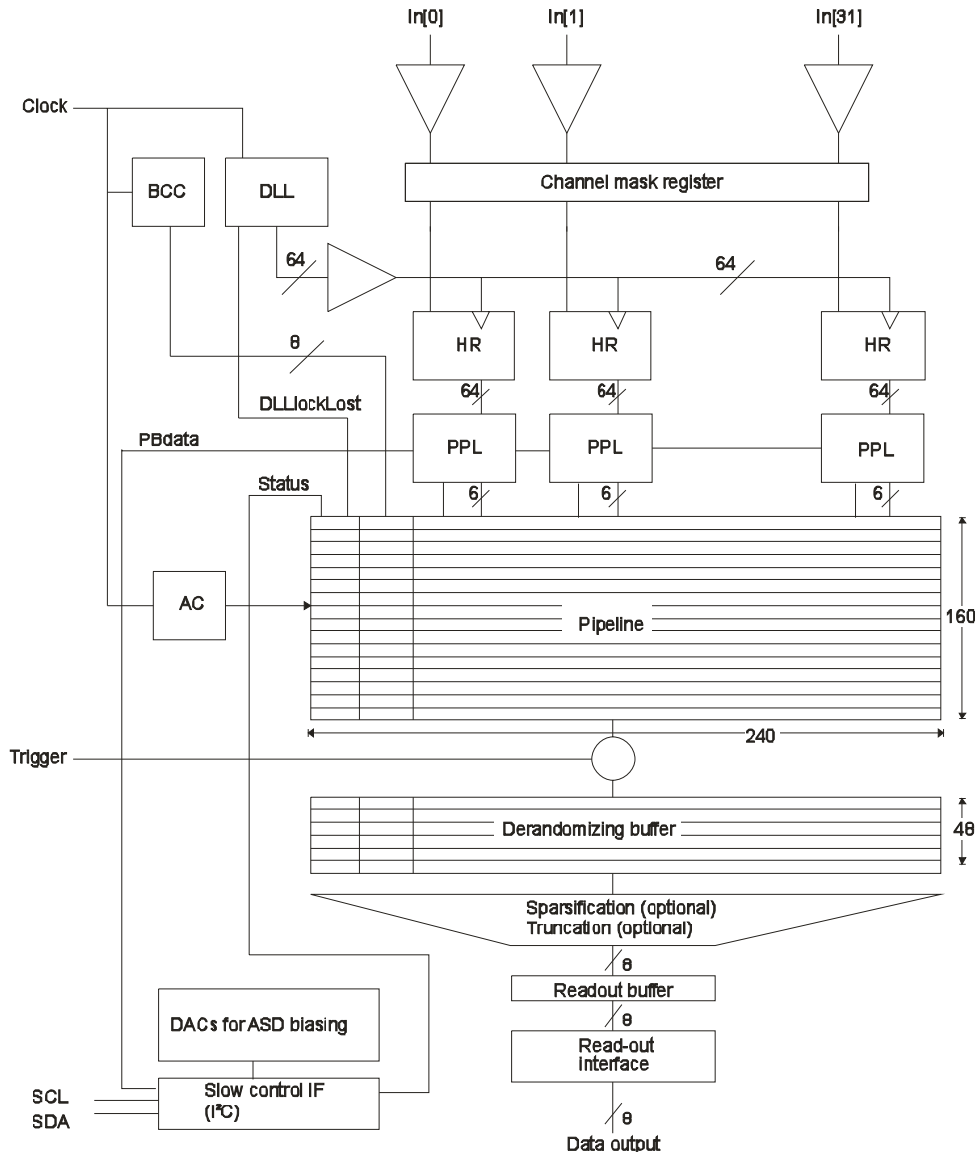


OTIS TDC Chip

Components:

- **32 maskable channels**
- **DLL, HitRegister, PrePipeline:**
6 bit drift time encoding:
1 bit $\leftrightarrow$ 0.39 ns (req. resolut. < 1ns)
playback data feed-in (testing)
- **Pipeline, Derandomizing Buffer:**
buffer length: 160 evts $\leftrightarrow$ 4.0 μ s
- **Control Algorithm:**
Memory and trigger management,
2 read-out modes: 1, 2, 3 BX/evt
- **I2C Slow Control Interface:**
Programming, ASD bias setting
- **DAC:** ASD-Chip bias

$\Rightarrow$ **0.25 μ m CMOS technology**



OTIS Readout Modes

Problem: max. drift-time 42 ns

→ min. 2 BX / evt

I. All hits of n BX with possible truncation for length > 36 bytes:

→ variable event length

Bit	0..31	32..95	96..101	...	90+(6n)...95+(6n)
Data	Header	2 * Hit-Info	Drift Time 1	...	Drift Time n

II. Single (first) hit mode

→ fixed event length

Bit	0 .. 31	32 .. 39	...	280 .. 287
Data	Header	time 0	...	time 31

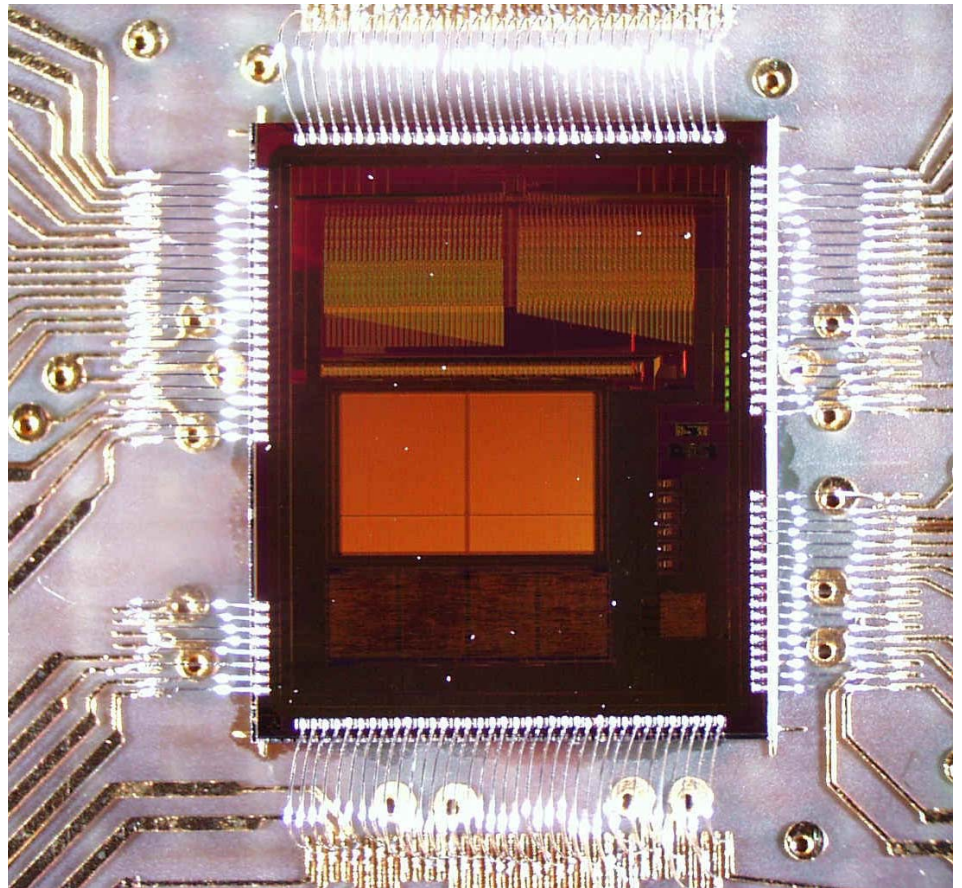
preferred readout mode

⇒ 320 Mbit/s @ 1.1 MHz L0

Hit Position	Data
1. BX	00xxxxxxx
2. BX	01xxxxxxx
3. BX	10xxxxxxx
no Hit	11xxxxxxx

OTIS1.0 Prototype

- First prototype with basic functionality
- ~700.000 transistors
- 5100 μ m x 6000 μ m
- Submission: 15/04/2002
Delivery: 29/07/2002
- Small test PCB:
possibility to connect ASD and GOL chips



OTIS1.0 Status

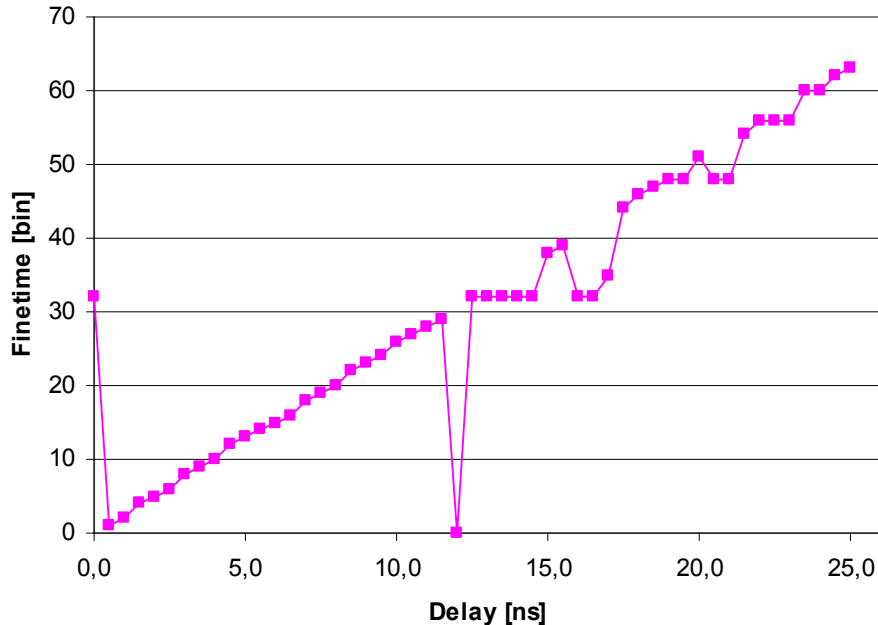
DLL Lock Range	29-56 MHz @ 300K 10-90°C @ 40 MHz
DLL Lock Time	$\leq 1\mu\text{s}$
DLL DNL	$0,51 \pm 0,03 \text{ LSB } (\approx 190\text{ps})$

} DLL test
chip

PowerUp Reset	as expected
Power Consumption	550mW
DLL: Lock Time	$\leq 1\mu\text{s}$
Lock Lost	not observed
DAC	as expected
Slow Control	as expected
Fast Control: Memory, Data Output, Debug Features	no errors found
Memory Selftest	timing problems
Drift Time Encoding	timing problems

} good
progress

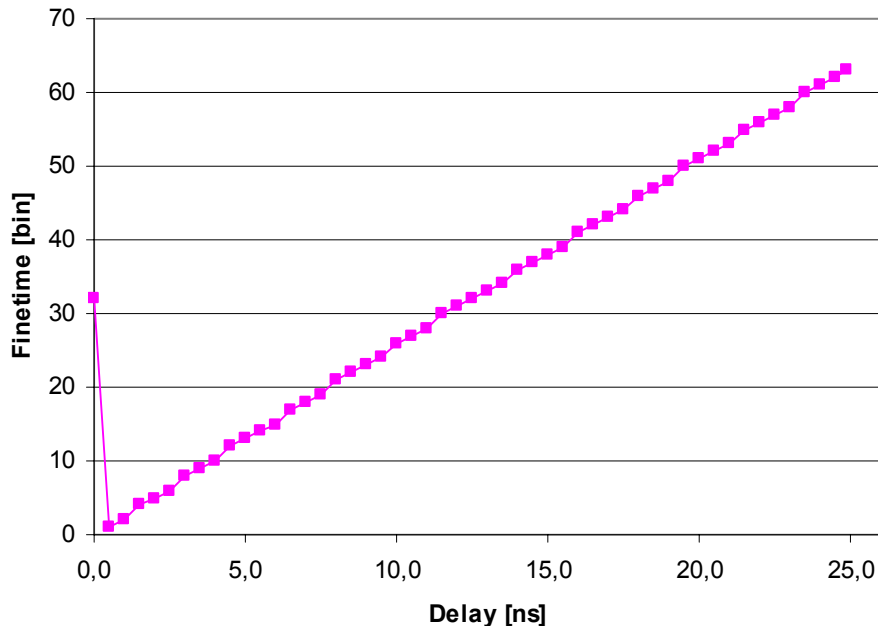
Finetime vs. Hitposition "Single Hit"



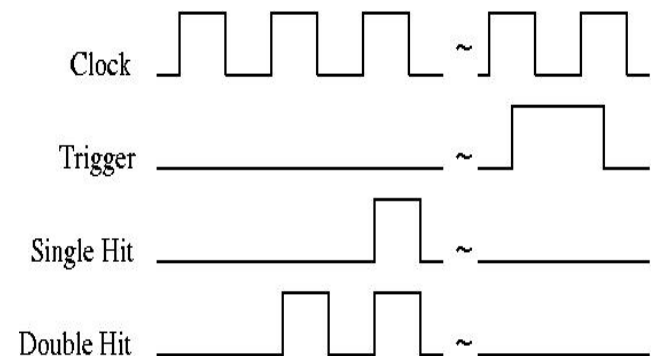
Drift time measurement:

- ← • In 2nd half of BX clock times are not correctly encoded:
studies (measurements and simulation) revealed timing problems between data bits and Clk signal at memory input
reason : parasitic capacities

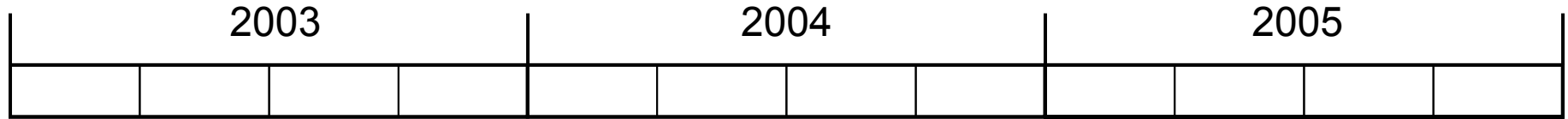
Finetime vs. Hitposition "Double Hit"



- ← • Double hit measurement:
1st hit to pre-charge



OTIS Time Schedule



03/03 OTIS chip review

↔ MPW11: Submission OTIS1.1

07/03 Validation of OTIS baseline

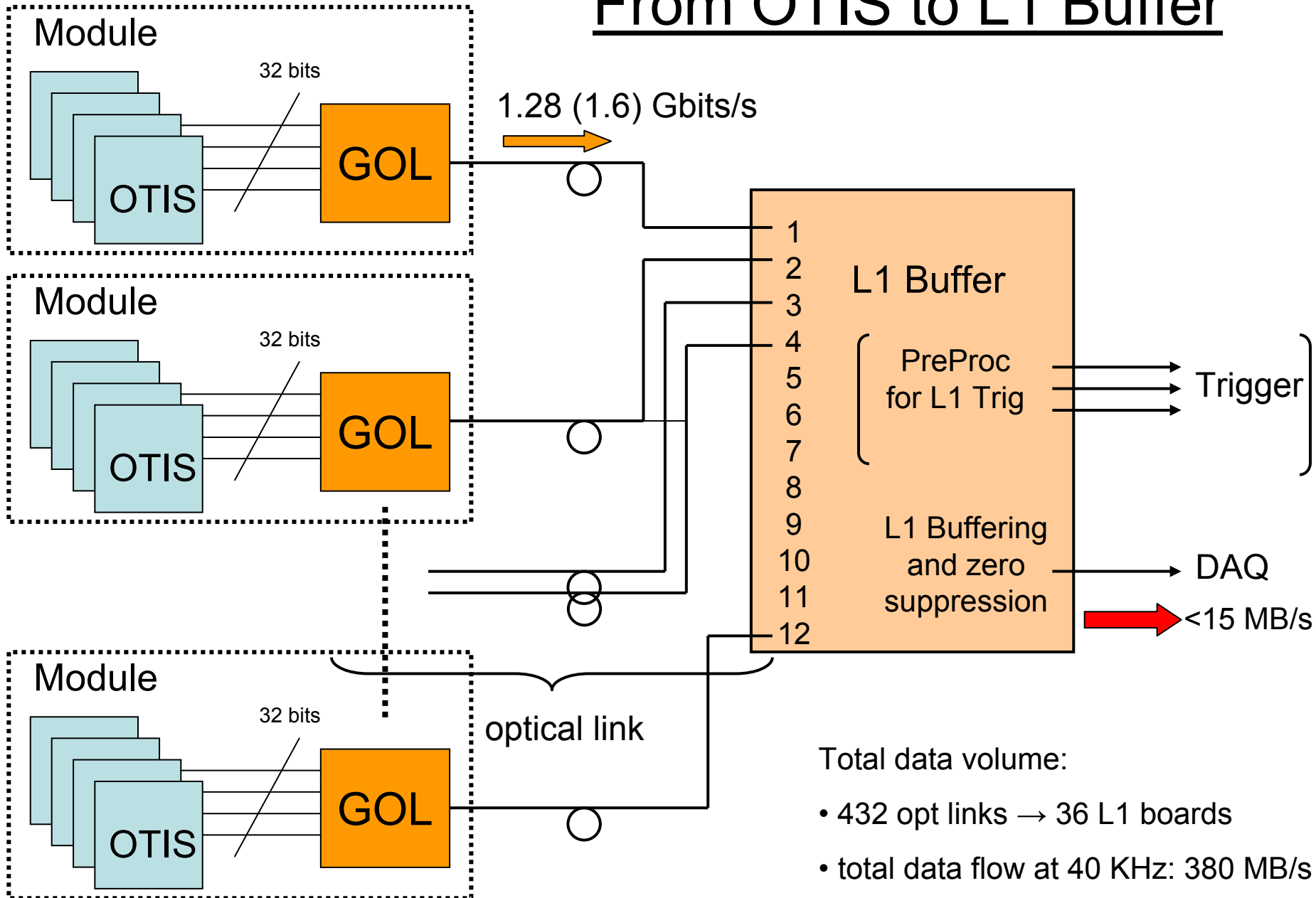
↔ Delivery of OTIS1.1 – Start of test

10/04 OTIS 1.2 Engineering Run

01/05 Delivery of OTIS1.2

03/05 Start Electr Prod

From OTIS to L1 Buffer



Test bench

RATOS
Optical
Transceiver →

GOL →

VCSEL

EV2-C Layer 1

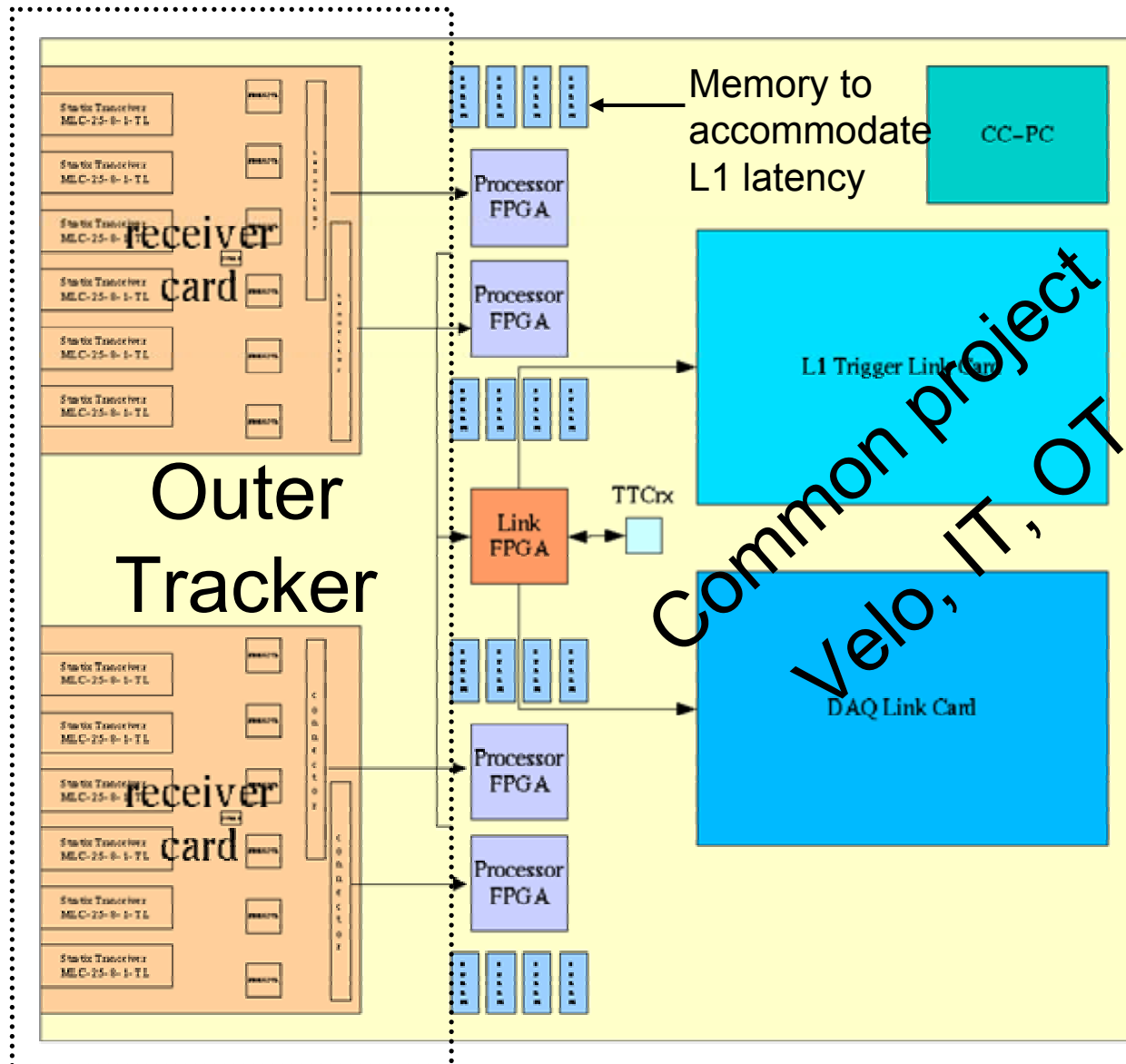
ALTERA
ACEX™
EPW 10K10C-1
Q 08C1007HAK

FANOUT

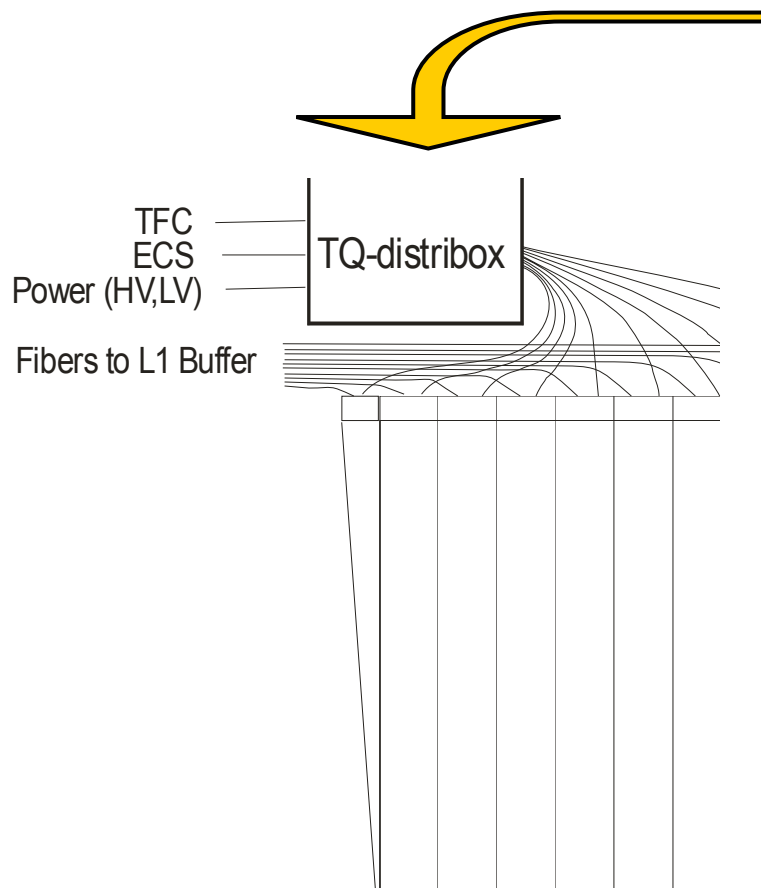


⇒ Error rate $< 10^{-13}$

L1 Buffer Board:



Services:



1 service box / quadrant

Service Box

TFC:

TTCrx + Rst Decoder → LVDS Signals → modules

ECS:

SPECS Slave → I2C bus lines → modules
→ JTAG → ADCs → LV sensing

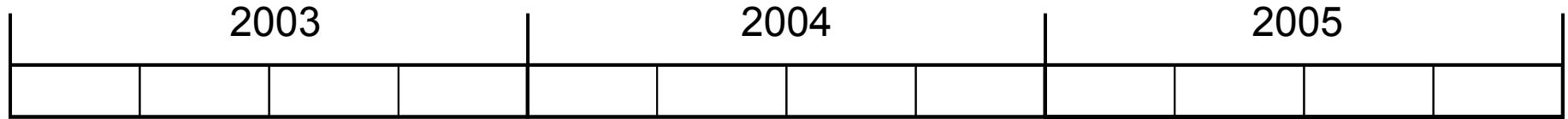
Low Voltage:

passive +/- 5V distribution → modules

High Voltage:

passive distribution → 2 connections/modules

Outer Tracker Electronics: Time Schedule



07/03 Validation of OTIS baseline

10/03 Delivery of OTIS1.1

03/04 Start pre-series production

06/04 Pre-series finished: start mounting

01/05 Delivery of OTIS1.2

03/05 Start Mass Prod